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Title: Spectroscopic Imaging Ellipsometry of Self-Assembled SiGe/Si Nanostructures

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Highlights:

- Imaging ellipsometry allows to investigate the optical response of SiGe/Si nanowires
- Spectroscopic measurements enable study of both structural and optical properties
- Inhomogeneous Ge content of different film regions is identified
- Measured anisotropic response of nanowires is ascribed to waveguide-like resonances

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